National Semiconductor

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MM54HC259/MM74HC259
8-Bit Addressable Latch/3-to-8 Line Decoder

General Description

This device utilizes advanced silicon-gate CMOS technology to implement an 8-bit addressable latch, designed for general purpose storage applications in digital systems.

The MM54HC259/MM74HC259 has a single data input (D), 8 latch outputs (Q1–Q8), 3 address inputs (A, B, and C), a common enable input ($\overline{G}$), and a common CLEAR input. To operate this device as an addressable latch, data is held on the D input, and the address of the latch into which the data is to be entered is held on the A, B, and C inputs. When ENABLE is taken low the data flows through to the addressed output. The data is stored when ENABLE transitions from low to high. All unaddressed latches will remain unaffected. With enable in the high state the device is deselected, and all latches remain in their previous state, unaffected by changes on the data or address inputs. To eliminate the possibility of entering erroneous data into the latches, the enable should be held high (inactive) while the address lines are changing.

If enable is held high and CLEAR is taken low all eight latches are cleared to a low state. If enable is low all latches except the addressed latch will be cleared. The addressed latch will instead follow the D input, effectively implementing a 3-to-8 line decoder.

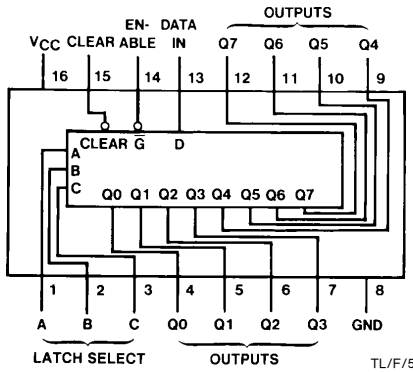
All inputs are protected from damage due to static discharge by diodes to V_{CC} and ground.

Features

- Typical propagation delay: 18 ns
- Wide supply range: 2–6V
- Low input current: 1 μA maximum
- Low quiescent current: 80 μA maximum (74HC Series)

Connection Diagram

Dual-In-Line Package



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Top View

Order Number MM54HC259 or MM74HC259

Latch Selection Table

Select Inputs			Latch Addressed
C	B	A	
L	L	L	0
L	L	H	1
L	H	L	2
L	H	H	3
H	L	L	4
H	L	H	5
H	H	L	6
H	H	H	7

H = high level, L = low level

D = the level at the data input

Q_{i0} the level of Q_i (i = 0, 1 . . . 7, as appropriate) before the indicated steady-state input conditions were established.

Truth Table

Inputs		Outputs of Addressed Latch	Each Other Output	Function
Clear	$\overline{G}$			
H	L	D	Q_{i0}	Addressable Latch
H	H	Q_{i0}	Q_{i0}	Memory
L	L	D	L	8-Line Decoder
L	H	L	L	Clear

RRD-B30M115/Printed in U. S. A.

Absolute Maximum Ratings (Notes 1 & 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5 to +7.0V
DC Input Voltage (V_{IN})	−1.5 to V_{CC} +1.5V
DC Output Voltage (V_{OUT})	−0.5 to V_{CC} +0.5V
Clamp Diode Current (I_{IK}, I_{OK})	±20 mA
DC Output Current, per pin (I_{OUT})	±25 mA
DC V_{CC} or GND Current, per pin (I_{CC})	±50 mA
Storage Temperature Range (T_{STG})	−65°C to +150°C
Power Dissipation (P_D) (Note 3)	600 mW
S.O. Package only	500 mW
Lead Temperature (T_L) (Soldering 10 seconds)	260°C

Operating Conditions

		Min	Max	Units
Supply Voltage (V_{CC})		2	6	V
DC Input or Output Voltage (V_{IN}, V_{OUT})		0	V_{CC}	V
Operating Temp. Range (T_A)				
MM74HC		−40	+85	°C
MM54HC		−55	+125	°C
Input Rise or Fall Times (t_r, t_f)	V_{CC} = 2.0V		1000	ns
	V_{CC} = 4.5V		500	ns
	V_{CC} = 6.0V		400	ns

DC Electrical Characteristics (Note 4)

Symbol	Parameter	Conditions	V_{CC}	T_A = 25°C	74HC T_A = −40 to 85°C	54HC T_A = −55 to 125°C	Units
				Typ	Guaranteed Limits		
V_{IH}	Minimum High Level Input Voltage		2.0V		1.5	1.5	1.5	V
			4.5V		3.15	3.15	3.15	V
			6.0V		4.2	4.2	4.2	V
V_{IL}	Maximum Low Level Input Voltage**		2.0V		0.5	0.5	0.5	V
			4.5V		1.35	1.35	1.35	V
			6.0V		1.8	1.8	1.8	V
V_{OH}	Minimum High Level Output Voltage	V_{IN} = V_{IH} or V_{IL} $\|I_{OUT}\| \le 20\ \mu A$	2.0V	2.0	1.9	1.9	1.9	V
			4.5V	4.5	4.4	4.4	4.4	V
			6.0V	6.0	5.9	5.9	5.9	V
		V_{IN} = V_{IH} or V_{IL} $\|I_{OUT}\| \le 4.0$ mA	4.5V	4.2	3.98	3.84	3.7	V
		$\|I_{OUT}\| \le 5.2$ mA	6.0V	5.7	5.48	5.34	5.2	V
V_{OL}	Maximum Low Level Output Voltage	V_{IN} = V_{IH} or V_{IL} $\|I_{OUT}\| \le 20\ \mu A$	2.0V	0	0.1	0.1	0.1	V
			4.5V	0	0.1	0.1	0.1	V
			6.0V	0	0.1	0.1	0.1	V
		V_{IN} = V_{IH} or V_{IL} $\|I_{OUT}\| \le 4.0$ mA	4.5V	0.2	0.26	0.33	0.4	V
		$\|I_{OUT}\| \le 5.2$ mA	6.0V	0.2	0.26	0.33	0.4	V
I_{IN}	Maximum Input Current	V_{IN} = V_{CC} or GND	6.0V		±0.1	±1.0	±1.0	μA
I_{CC}	Maximum Quiescent Supply Current	V_{IN} = V_{CC} or GND I_{OUT} = 0 μA	6.0V		8.0	80	160	μA

Note 1: Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: −12 mW/°C from 65°C to 85°C; ceramic "J" package: −12 mW/°C from 100°C to 125°C.

Note 4: For a power supply of 5V ±10% the worst case output voltages (V_{OH}, and V_{OL}) occur for HC at 4.5V. Thus the 4.5V values should be used when designing with this supply. Worst case V_{IH} and V_{IL} occur at V_{CC} = 5.5V and 4.5V respectively. (The V_{IH} value at 5.5V is 3.85V.) The worst case leakage current (I_{IN}, I_{CC}, and I_{OZ}) occur for CMOS at the higher voltage and so the 6.0V values should be used.

**V_{IL} limits are currently tested at 20% of V_{CC}. The above V_{IL} specification (30% of V_{CC}) will be implemented no later than Q1, CY'89.

AC Electrical Characteristics (V_{CC} = 5.0V, T_A = 25°C, $t_r = t_f$ = 6 ns, C_L = 15 pF unless otherwise specified.)

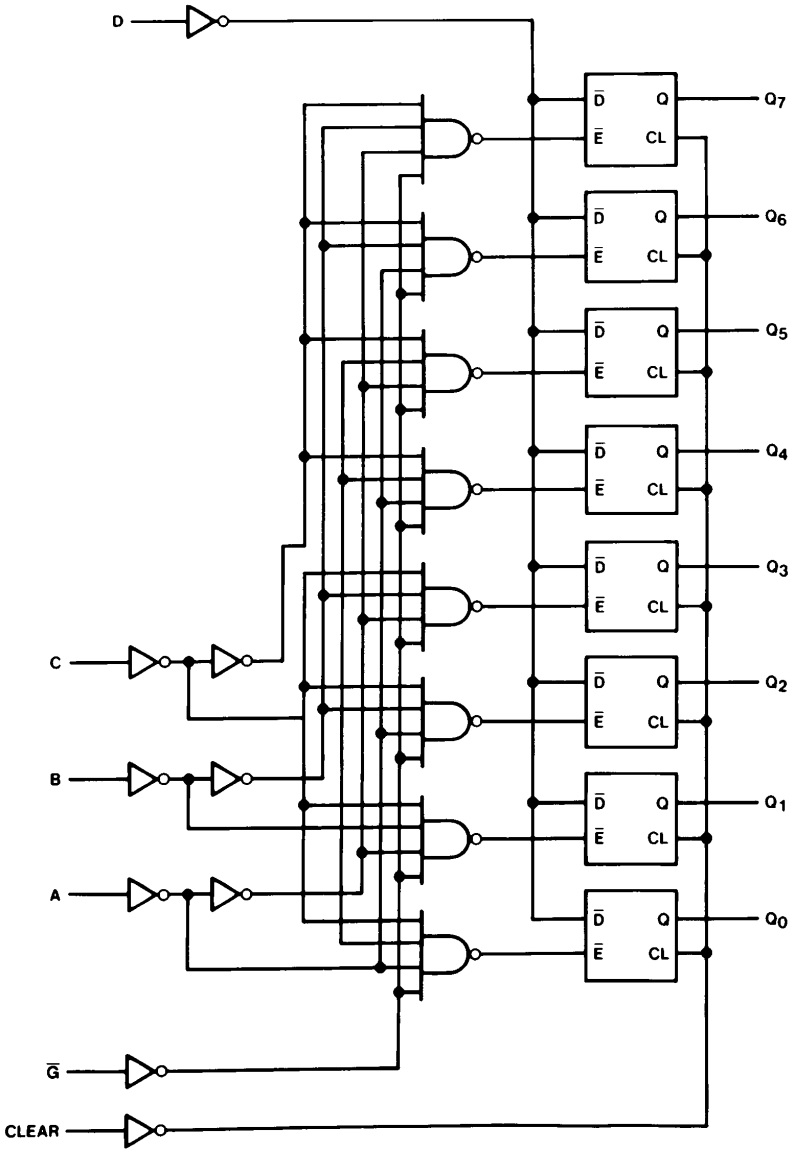
Symbol	Parameter	Conditions	Typ	Guaranteed Limit	Units
t_{PHL}, t_{PLH}	Maximum Propagation Delay Data to Output		18	32	ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay Select to Output		20	38	ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay Enable to Output		20	35	ns
t_{PHL}	Maximum Propagation Delay Clear to Output		17	27	ns
t_W	Minimum Enable Pulse Width		10	16	ns
t_W	Minimum Clear Pulse Width		10	16	ns
t_r, t_f	Maximum Input Rise and Fall Time			500	ns
t_s	Minimum Setup Time Select or Data to Enable		15	20	ns
t_H	Minimum Hold Time Data or Address to Enable		−2	0	ns

AC Electrical Characteristics $t_r = t_f$ = 6 ns, C_L = 50 pF, V_{CC} = 2.0V–6.0V

Symbol	Parameter	Conditions	V_{CC}	T_A = 25°C	74HC T_A = −40 to 85°C	54HC T_A = −55 to 125°C	Units
				Typ	Guaranteed Limits		
t_{PHL}, t_{PLH}	Maximum Propagation Delay Data to Output		2.0V 4.5V 6.0V	60 19 17	180 37 32	225 46 40	250 52 45	ns ns ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay Select to Output		2.0V 4.5V 6.0V	72 21 18	220 43 37	275 54 46	310 60 52	ns ns ns
t_{PHL}, t_{PLH}	Maximum Propagation Delay Enable to Output		2.0V 4.5V 6.0V	65 27 23	200 40 35	250 50 44	280 58 50	ns ns ns
t_{PHL}	Maximum Propagation Delay Clear to Output		2.0V 4.5V 6.0V	50 18 16	150 31 26	190 39 32	210 44 37	ns ns ns
t_W	Minimum Pulse Width Clear or Enable		2.0V 4.5V 6.0V		80 16 14	100 20 18	120 24 20	ns ns ns
t_s	Minimum Setup Time Address or Data to Enable		2.0V 4.5V 6.0V		100 20 15	125 25 19	150 28 25	ns ns ns
t_H	Minimum Hold Time Address or Data to Enable		2.0V 4.5V 6.0V	−10 −2 −2	0 0 0	0 0 0	0 0 0	ns ns ns
t_{TLH}, t_{THL}	Maximum Output Rise and Fall Time		2.0V 4.5V 6.0V	30 8 7	75 15 13	95 19 16	110 22 19	ns ns ns
C_{IN}	Input Capacitance			5	10	10	10	pF
C_{PD}	Power Dissipation Capacitance (Note 5)	(per package)		80				pF

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} s V_{CC} s f + I_{CC}$.

Logic Diagram



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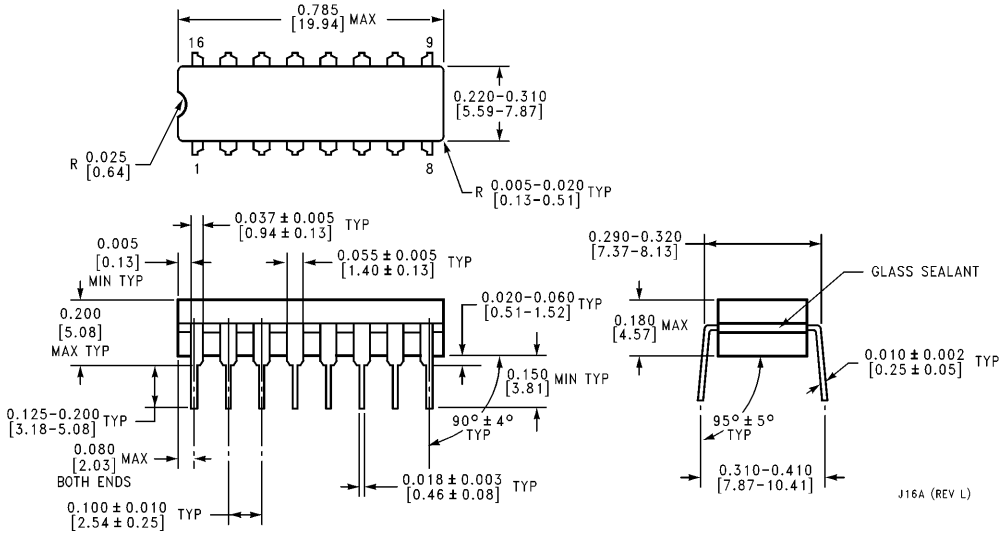
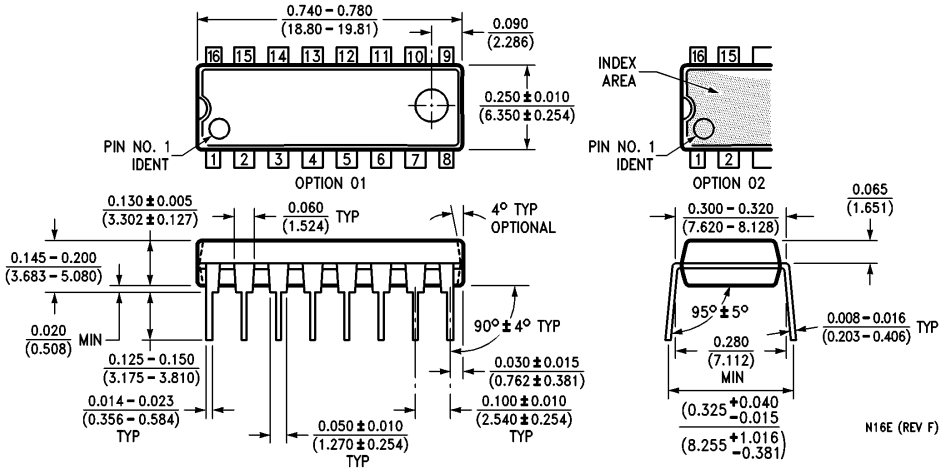
Physical Dimensions inches (millimeters)



Dual-In-Line Package
Order Number MM54HC259J or MM74HC259J,N
NS Package J16A

Physical Dimensions inches (millimeters) (Continued)



Dual-In-Line Package
Order Number MM74HC259N
NS Package N16E

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